


<div>Search Notes</div> <div></div>	Application/Control No.	Applicant(s)/Patent under Reexamination	
	09/727,491	CHEN ET AL.	
	Examiner	Art Unit	
	Cong-Lac Huynh	2178	

SEARCHED			
Class	Subclass	Date	Examiner
715	500.1	11/30/2005	CLH
	723	11/30/2005	CLH

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
East	11/30/2005	CLH
ACM	11/30/2005	CLH
IEEE	11/30/2005	CLH